

PREFACE

This volume contains 78 contributions to the 3rd International Autumn Meeting "Gettering and Defect Engineering in the Semiconductor Technology - GADEST'89". For some missing papers the abstracts were printed.

According to invitations and to the submission of abstracts 84 papers by authors from more than 60 research institutes of 22 countries were accepted for presentation at GADEST'89 and will give a representative survey of the international state of knowledge. Because of the large number of papers submitted introduction of poster sessions to GADEST'89 became necessary.

The large interest emphasizes the significance of the chosen profile of the meeting serving as a forum both for providing deeper insight into defects in semiconductors and for discussing important effects gettering and defect engineering may have in the dynamically developing microelectronics technology.

GADEST'89 is organized by the Institute of Semiconductor Physics of the Academy of Sciences of the GDR with support given by the Academy of Sciences of the GDR and the VEB Kombinat Mikroelektronik Erfurt. The dedicated work of the Organizing Committee is gratefully acknowledged. Special thanks are due to C. Becker.

Finally, the 4th International Autumn Meeting GADEST'91 will be held in October 1991.

Frankfurt (Oder)
June, 1989

Martin Kittler
Chairman GADEST'89

